

**Amendments to the Claims:**

Please cancel claims 1-19 as presented in the underlying International Application No. PCT/EP2004/052296 and add new claims 20-40 as shown in the listing of claims.

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

Claims 1-19 (canceled).

Claim 20 (new):       A scanning microscope comprising:  
                  a light source configured to evanescently illuminate a sample disposed on a slide;  
                  a point detector configured to receive detection light emanating from a scanning point of the sample; and  
                  a beam deflection device disposed in an optical path of the detection light and configured to shift a position of the scanning point.

Claim 21 (new):       The scanning microscope as recited in claim 20 wherein the light source is configured to evanescently illuminate the sample by providing illuminating light, the illuminating light being coupled into the slide or into a cover slip of the sample.

Claim 22 (new):       The scanning microscope as recited in claim 21 wherein the scanning microscope comprises a condenser configured to couple the illuminating light into the slide through the condenser.

Claim 23 (new):       The scanning microscope as recited in claim 21 further comprising an objective lens configured to couple the illuminating light into the cover slip through the objective

lens.

Claim 24 (new): The scanning microscope as recited in claim 23 wherein the objective lens has an objective pupil, the illuminating light passing through an outer edge region thereof.

Claim 25 (new): The scanning microscope as recited in claim 24 wherein the illuminating light propagates in an illuminating light beam.

Claim 26 (new): The scanning microscope as recited in claim 24 wherein the illuminating light beam forms a focus in a plane of the objective pupil.

Claim 27 (new): The scanning microscope as recited in claim 25 further comprising an additional beam deflection device disposed in an optical path of the illuminating light and configured to change a spatial position of the illuminating light beam.

Claim 28 (new): The scanning microscope as recited in claim 27 wherein the additional beam deflection device is configured to direct the illuminating light beam in circles through the outer edge region of the objective pupil.

Claim 29 (new): The scanning microscope as recited in claim 23 wherein the objective lens has a numerical aperture greater than 1.3.

Claim 30 (new): The scanning microscope as recited in claim 29 wherein the objective lens has a numerical aperture between 1.35 and 1.42.

Claim 31 (new): The scanning microscope as recited in claim 20 further comprising a color-selective segmented aperture disposed in an optical path of the illuminating light.

Claim 32 (new): The scanning microscope as recited in claim 31 further comprising an

objective lens having an objective pupil, and wherein the color-selective segmented aperture is disposed in a plane of the objective pupil.

Claim 33 (new): The scanning microscope as recited in claim 31 wherein an outer edge region of the color-selective segmented aperture is transparent to light having a wavelength of the illuminating light.

Claim 34 (new): The scanning microscope as recited in claim 33 wherein an inner edge region of the color-selective segmented aperture is transparent only to light having a wavelength greater than the wavelength of the illuminating light.

Claim 35 (new): The scanning microscope as recited in claim 33 wherein an inner edge region of the color-selective segmented aperture is transparent only to light having a wavelength below the wavelength of the illuminating light.

Claim 36 (new): The scanning microscope as recited in claim 35 wherein the illuminating light includes pulsed infrared light.

Claim 37 (new): The scanning microscope as recited in claim 20 wherein the illuminating light includes a plurality of wavelengths.

Claim 38 (new): The scanning microscope as recited in claim 20 wherein the point detector includes at least one of a multi-band detector and a spectrometer.

Claim 39 (new): The scanning microscope as recited in claim 20 wherein the point detector includes a detection pinhole.

Claim 40 (new): The scanning microscope as recited in claim 20 further comprising a

scanning unit configured to provide confocal scanning.